Lecture 1 – Combinatorial Testing

AAA705: Software Testing and Quality Assurance

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2024 Spring





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- It is also known as functional testing or behavioral testing.
- Test data are derived from the specification of the software.
- In general, exhaustive testing is not feasible. It means that we cannot guarantee that the software is free of defects.
- We need to pick a good set of test cases to maximize the chance of finding software errors.

Contents



- 1. Equivalence Partitioning (EP)
- 2. Boundary Value Analysis (BVA)
- 3. Category Partition Method (CPM)
- 4. Combinatorial Testing (CT)

Covering Array (CA)

Fault Detection Effectiveness

Greedy Algorithm – IPOG Strategy

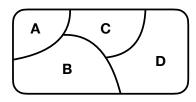
Greedy vs. Meta-heuristic

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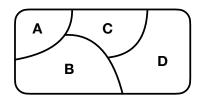
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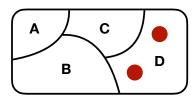
 Equivalence partitioning is a black-box testing technique that divides the input domain of a program into equivalence classes.





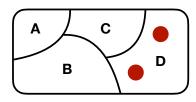
- Equivalence partitioning is a black-box testing technique that divides the input domain of a program into equivalence classes.
- The technique is based on the observation that the program should behave the same way for all members of an equivalence class.





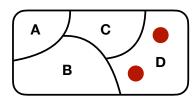
 If one test case in an equivalence class reveals an error, it is likely that other test cases in the same equivalence class will also reveal the same error.





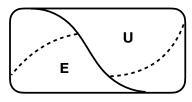
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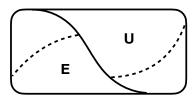
- If one test case in an equivalence class reveals an error, it is likely that other test cases in the same equivalence class will also reveal the same error.
- The idea is to reduce the number of test cases by selecting one test case from each equivalence class.
- Then, how to define the equivalence classes?





- One possible way to define the equivalence classes is to divide the input domain into expected and unexpected inputs.
 - Expected (E) or legal inputs
 - Unexpected (U) or illegal inputs





- One possible way to define the equivalence classes is to divide the input domain into expected and unexpected inputs.
 - Expected (E) or legal inputs
 - Unexpected (U) or illegal inputs
- We can further divide the expected inputs into smaller equivalence classes.



Example

Consider a program that takes a **password** as input. The length of the password must be between 6 and 20 characters.

- We can divide the input domain into two equivalence classes:
 - $E = \{ \text{ a password } p \mid 6 \le |p| \le 20 \}$
 - $U = \{ \text{ a password } p \mid |p| < 6 \lor |p| > 20 \}$



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- We can divide it more finely:
 - $E_1 = \{ \text{ a password } p \mid 6 \le |p| \le 10 \} \text{ for } weak \text{ passwords} \}$
 - $E_2 = \{ \text{ a password } p \mid 11 \leq |p| \leq 15 \}$ for medium-strength passwords
 - $E_3 = \{ \text{ a password } p \mid 16 \le |p| \le 20 \} \text{ for } \textit{strong passwords}$
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- We can select one test case from each equivalence class.

$$I = \{p_1, p_2, p_3, p_4, p_5\}$$

such that $|p_1| = 7$, $|p_2| = 13$, $|p_3| = 18$, $|p_4| = 3$, $|p_5| = 40$



• There are many ways to partition the input domain.

¹[TSE'91] E. J. Weyuker and B. Jeng, "Analyzing partition testing strategies"



- There are many ways to partition the input domain.
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Partition testing can be better, worse, or the same as random testing, depending on how the partitioning is done.¹

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Off-by-one Errors



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- Logic errors often occur at the boundaries of the input domain.
- They usually occur due to off-by-one errors caused by misunderstanding the boundary conditions.
- It is simple but actually very common.

Off-by-one Errors - Looping Over Arrays



```
for (let i = 0; i < 10; i++) {
  /* body of the loop */
}</pre>
```

```
for (let i = 1; i < 10; i++) {
   /* body of the loop */
}</pre>
```

CORRECT

INCORRECT

```
for (let i = 0; i <= 10; i++) {
  /* body of the loop */
}</pre>
```

```
for (let i = 0; i < 11; i++) {
   /* body of the loop */
}</pre>
```

INCORRECT

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Off-by-one Errors – Fencepost error



If you build a straight fence 15 meters long with posts spaced 3 meters apart, how many posts do you need?

$$15 / 3 = 5 \text{ posts}?$$

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$$15 / 3 = 5$$
 posts? No, you need 6 posts!

1	2	3	4	5
1 2	2 3	3 4	1 5	6

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Off-by-one Errors - strncat in C



```
void foo (char *s)
{
   char buf[15];
   memset(buf, 0, sizeof(buf));
   // Final parameter should be: sizeof(buf)-1
   strncat(buf, s, sizeof(buf));
}
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- For example, we need to subtract 1 byte from the length of the buffer in strncat but not in fgets or strncpy.

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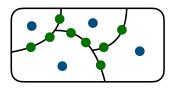


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- Off-by-one errors are common in using the C library because it is not consistent with respect to whether one needs to subtract 1 byte.
- For example, we need to subtract 1 byte from the length of the buffer in strncat but not in fgets or strncpy.
- So, the programmer has to remember for which functions they need to subtract 1.

Boundary Value Analysis (BVA)



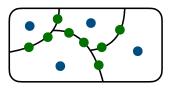


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- Boundary Value Analysis (BVA)

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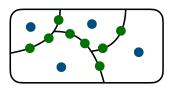




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- The idea is to select test cases at the **boundaries** of the equivalence classes.

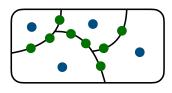




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- The technique is based on the observation that the program is more likely to fail at the **boundaries** of the input domain.
- It is usually used in combination with equivalence partitioning.



Example

Consider a program that takes a **password** as input. The length of the password must be between 6 and 20 characters.

- Consider the equivalence classes:
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- We can select test cases at the boundaries of the equivalence classes.

$$I = \{p_1, p_2, p_3, p_4, p_5, p_6, p_7, p_8\}$$

such that

$$|p_1| = 5$$
 $|p_2| = 6$ $|p_3| = 10$ $|p_4| = 11$
 $|p_5| = 15$ $|p_6| = 16$ $|p_7| = 20$ $|p_8| = 21$

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- Most programs behave differently when they receive different parameters or are executed under different environments.
- Category partition method (CPM) is a black-box testing technique that systematically generates test cases by considering the combinations of the categories of the input domain.
 - 1 Analyze specification
 - 2 Identify parameters and environments
 - 3 Identify categories for each parameter and environment
 - 4 Partition categories into equivalence classes
 - 6 Identify constraints
 - **6** Generate test cases



Example

Unix command grep searches for files in a directory hierarchy with the following syntax:

```
grep <pattern> <filename>
```

For example,

- grep park myfile displays all lines in myfile that contain the word "park".
- grep "hello world" myfile displays all lines in myfile that contain the phrase "hello world".
- grep " said \"hello " myfile displays all lines in myfile that contain the phrase " said "hello ".

Perform category partition method for the grep command.



- 1 Analyze specification
- 2 Identify parameters and environments
 - Parameters (1) <pattern> and (2) <filename>
 - The <pattern> is a pattern to search for.
 - To include spaces in the pattern, it must be enclosed in quotes (").
 - To include a quotation mark in the pattern, it must be escaped with a backslash (\").
 - ...
 - Environments (3) file contents
 - . . .



- ③ Identify categories for each parameter and environment
 - ① Parameter <pattern>
 - Size
 - Quotation marks
 - Embedded spaces
 - Embedded quotation marks
 - Parameter <filename>
 - Validity
 - **3 Environment** file contents
 - Number of occurrences of the pattern
 - Number of occurrences of the pattern in a line



- (4) Partition categories into equivalence classes
 - ① Parameter <pattern>
 - Size $-0/1/\ge 2$
 - Quotation marks quoted (Q) / unquoted (U) / improper (I)
 - Embedded spaces none (N) / single (S) / multiple (M)
 - Embedded quotation marks none (N) / single (S) / multiple (M)
 - Parameter <filename>
 - Validity exists (E) / not exists (N) / omitted (O)
 - **3 Environment** file contents
 - Number of occurrences of the pattern 0/1/2
 - Number of occurrences of the pattern in a line 0/1/2



How many combinations of the partitioned categories?

$$3 \times 3 \times 3 \times 3 \times 3 \times 3 \times 3 = 2,187$$



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- (5) Identify **constraints**
 - For example, no embedded space for unquoted pattern.
 - unquoted (U) $\Rightarrow \leftarrow$ single (S) for **embedded spaces** unquoted (U) $\Rightarrow \leftarrow$ multiple (M) for **embedded spaces**



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unquoted (U)
$$\Rightarrow \leftarrow$$
 single (S) for **embedded spaces** unquoted (U) $\Rightarrow \leftarrow$ multiple (M) for **embedded spaces**

- 6 Generate test cases
 - Pick one test case from each combination satisfying the constraints.

Size	Q	Space	Emb. Q	Valid	Occur	Occur
0	Q	N	N	Е	0	0
1	U	S	S	N	1	1
≥ 2		М	М	0	≥ 2	≥ 2

grep "hello world" myfile

`myfile` is an empty file

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 - For example, we need 1,799,736,525 test cases required for the following airport system:

Airline	Destination	Departure Date	Return Date
79	171	365	365



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 - For example, we need 1,799,736,525 test cases required for the following airport system:

Airl	ine	Destination	Departure Date	Return Date
79	9	171	365	365

 Combinatorial testing (CT) or combinatorial interaction testing (CIT) constructs test cases by considering the interactions between the parameters.

Covering Array (CA)



Definition (Interaction)

For k parameters with v values each, a t-way interaction is a combination of values for t parameters.

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Definition (Covering Array (CA))

A **covering array** A = CA(N; t, k, v) is a $N \times k$ matrix such that every field is an element from the set [0, v - 1], and every t-way interaction is covered at least once by a row of A.

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				CA(N = 4	1; t =	= 2,	<i>k</i> =	3, v =
Δ	R	(Α	В	С	
_	0	0			0	0	0	
0	0	0	_		0	1	1	
1	1	1			1	0	1	
					1	1	0	

Mixed Covering Array (MCA)



Definition (Mixed Covering Array (MCA))

A mixed covering array $A = CA(N; t, k, v = (v_1, v_2, ..., v_k))$ is a $N \times k$ matrix such that every field in the *i*-th column is an element from the set $[0, v_i - 1]$, and every *t*-way interaction is covered at least once by a row of A.

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A mixed covering array $A = CA(N; t, k, v = (v_1, v_2, \dots, v_k))$ is a $N \times k$ matrix such that every field in the i-th column is an element from the set $[0, v_i - 1]$, and every t-way interaction is covered at least once by a row of Α.

$$CA(N = 6; t = 2, k = 3, v = (2, 2, 3))$$

A	В	C	
0	0	0	
1	1	1	
		2	



_	-,				
Α	В	С			
0	0	0			
0	1	1			
1	0	2			
1	1	0			
1	0	1			
0	1	2			

Constraint Mixed Covering Array (CMCA)



Definition (Constrinat Mixed Covering Array (CMCA))

A **mixed covering array** $A = CA(N; t, k, v = (v_1, v_2, ..., v_k), P)$ is a $N \times k$ matrix such that every field in the *i*-th column is an element from the set $[0, v_i - 1]$, and every **valid** t-way interaction is covered at least once by a row of A. We say that a t-way interaction is **valid** if it satisfies the predicate P.

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A **mixed covering array** $A = CA(N; t, k, v = (v_1, v_2, ..., v_k), P)$ is a $N \times k$ matrix such that every field in the *i*-th column is an element from the set $[0, v_i - 1]$, and every **valid** t-way interaction is covered at least once by a row of A. We say that a t-way interaction is **valid** if it satisfies the predicate P.

	Α	В	С		CA(N	J = 5; t =	= 2,	k =	3, <i>v</i>	= (2,	2, 3)	, P)
	Λ.	0	0				A	В	C			
	1	1	1				0	1	1			
	1	1	1	\Rightarrow			1	0	2			
							1	1	0			
D(v		.,	1	> 0			1	0	1			
P(x)	<i>, y)</i>	= x	+ <i>y</i>	> 0			0	1	2			



Definition (Combinatorial Testing (CT))

Combinatorial testing with a strength t produces a test suite from a covering array CA(N; t, k, v) for a system with k parameters, each with



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Pairwise testing is a special case of combinatorial testing with t = 2.

Pairwise testing produces 5 test cases for the following system:

$$\begin{array}{c|cccc}
A & B & C \\
\hline
0 & 0 & 0 \\
\hline
1 & 1 & 1 \\
& & 2
\end{array}$$

$$P(x,y) = x + y > 0$$

$$CA(N = 5; t = 2, k = 3, v = (2, 2, 3), P)$$

Α	В	С
0	1	1
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\end{array}
\Rightarrow$$

$$P(x,y) = x + y > 0$$

$$CA(N = 5; t = 2, k = 3, v = (2, 2, 3), P)$$

Α	В	С
0	1	1
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- Pairwise testing is a good trade-off between test effort and test effectiveness.
 - For a system with 20 parameters each with 15 values, **pairwise testing** only requires 412 tests, whereas exhaustive testing requires $15^{20} = 3.5 \times 10^{25}$ tests.

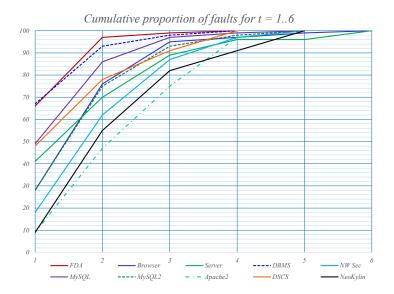


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- Is higher strength always better for fault detection?
- It depends on the target program, but we can analyze the general trend against a set of known faults.
 - Pairwise testing discovers at least 53% of the known faults.
 - 6-way testing discovers 100% of the known faults.





"Combinatorial Methods in Software Testing" by Rick Kuhn, NIST,

Greedy Algorithm - IPOG Strategy



- The problem of generating a minimum covering array is NP-complete.
 - It can be reduced to the **vertex cover problem**.

²[ECBS'07] LEI, Yu, et al. "IPOG: A general strategy for t-way software testing.



- The problem of generating a minimum covering array is NP-complete.
 - It can be reduced to the **vertex cover problem**.
- Let's learn a polynomial time greedy algorithm called IPOG (In-Parameter-Order-General)² that generates a covering array with a strength t. It is not optimal but practical.

²[ECBS'07] LEI, Yu, et al. "IPOG: A general strategy for t-way software testing.



- 1 Initialize **test set** *ts* to be an empty set.
- **2** Parameters are P_1, P_2, \ldots, P_k .
- **3** Add a test into *ts* for **all interactions of the first** *t* **parameters**.
- 4 for $(i = t + 1; i \le n; i++)$ (Horizontal Growth)
 - **1** Let π be the **set of** t-way interactions involving parameter P_i and t-1 parameters among the first i-1 parameters.
 - **2** for (test $\gamma = (v_1, v_2, \dots, v_{i-1}) \in ts$)
 - **1** Choose a value v_i of P_i
 - **2** Replace γ with $\gamma' = (v_1, v_2, \dots, v_{i-1}, v_i)$ such that γ' covers the most number of interactions in π .
 - **3** Remove from π the interaction covered by γ' .
- **5** for (interaction $\alpha \in \pi$) (Vertical Growth)
 - **1** if (\exists a test covers α) **Remove** α from π .
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- 1 Initialize **test set** *ts* to be an empty set.
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- 3 Add a test into ts for all interactions of the first t parameters.



Example

We want to **pairwise testing** for the following system:

P_1	P_2	P_3
0	0	0
1	1	1
		2

Adding all combinations of values between the first 2 parameters:

$$ts = egin{array}{|c|c|c|c|} \hline P_1 & P_2 \\ \hline 0 & 0 \\ 0 & 1 \\ \hline 1 & 0 \\ \hline 1 & 1 \\ \hline \end{array}$$



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 - 1 Let π be the set of t-way interactions involving parameter P_i and t-1 parameters among the first i-1 parameters.

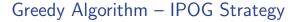


Set π as pairs to cover involving P_3 :

	P_1	P_2	P_3
	0		0
		0	0
	0		1
		0	1
	0		2
$\pi =$		0	2
	1		0
		1	1 2 2 0 0
	1		1
		1	1
	1		1 2 2
		1	2



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$$ts = egin{array}{|c|c|c|c|c|} \hline P_1 & P_2 & P_3 \\ \hline 0 & 0 & \\ 0 & 1 & \\ \hline 1 & 0 & \\ \hline 1 & 1 & \\ \hline \end{array}$$

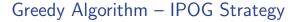
	P_1	P_2	P_3
	0		0
		0	0
	0		1
		0	1 2 2 0 0
	0		2
$\pi =$		0	2
	1		0
		1	
	1		1
		1	1
	1		1 2 2
		1	2





$$ts = egin{array}{|c|c|c|c|c|} \hline P_1 & P_2 & P_3 \\ \hline 0 & 0 & 0 \\ \hline 0 & 1 \\ \hline 1 & 0 \\ \hline 1 & 1 \\ \hline \end{array}$$

	P_1	P_2	P_3
	0		0
		0	0
	0		1
		0	1
	0		2 2 0 0
$\pi =$		0	2
	1		0
		1	
	1		1
		1	1
	1		1 2 2
		1	2





$$ts = \begin{array}{|c|c|c|c|}\hline P_1 & P_2 & P_3 \\ \hline 0 & 0 & 0 \\ \hline 0 & 1 & 1 \\ \hline 1 & 0 \\ \hline 1 & 1 \\ \hline \end{array}$$

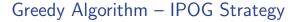
	P_1	P_2	P_3
	0		0
		0	0
	0		1
		0	1
	0		2 2 0
$\pi =$		0	2
	1		0
		1	0
	1		1
		1	1
	1	·	2 2
		1	2





$$ts = \begin{bmatrix} P_1 & P_2 & P_3 \\ \hline 0 & 0 & 0 \\ \hline 0 & 1 & 1 \\ \hline 1 & 0 & 1 \\ \hline 1 & 1 & \end{bmatrix}$$

	P_1	P_2	P_3
	0		0
		0	0
	0		1
		0	1 2 2 0 0
	0		2
$\pi =$		0	2
	1		0
		1	
	1		1
		1	1
	1		1 2 2
		1	2





$$ts = egin{array}{|c|c|c|c|c|} \hline P_1 & P_2 & P_3 \\ \hline 0 & 0 & 0 \\ 0 & 1 & 1 \\ \hline 1 & 0 & 1 \\ 1 & 1 & 0 \\ \hline \end{array}$$

	P_1	P_2	P_3
	0		0
		0	
	0		1
		0	1
	0		2 2 0
$\pi =$		0	2
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		1	0
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Extending ts:

$$ts = egin{array}{|c|c|c|c|c|} \hline P_1 & P_2 & P_3 \\ \hline 0 & 0 & 0 \\ 0 & 1 & 1 \\ \hline 1 & 0 & 1 \\ 1 & 1 & 0 \\ \hline \end{array}$$

	P_1	P_2	P_3
	0		0
		0	
	0		1
		0	1 2 2 0
	0		2
$\pi =$		0	2
	1		0
		1	0
	1		1
		1	1
	1		2 2
		1	2





Extending ts:

$$ts = egin{array}{|c|c|c|c|c|} \hline P_1 & P_2 & P_3 \\ \hline 0 & 0 & 0 \\ \hline 0 & 1 & 1 \\ \hline 1 & 0 & 1 \\ \hline 1 & 1 & 0 \\ \hline 0 & 0 & 2 \\ \hline \end{array}$$

	P_1	P_2	P_3
	0		0
		0	
	0		1
		0	1
	0		2 2 0
$\pi =$		0	2
	1		0
		1	0
	1		1
		1	1
	1		1 2 2
		1	2





Extending ts:

$$ts = egin{array}{|c|c|c|c|c|} \hline P_1 & P_2 & P_3 \\ \hline 0 & 0 & 0 \\ \hline 0 & 1 & 1 \\ \hline 1 & 0 & 1 \\ \hline 1 & 1 & 0 \\ \hline 0 & 0 & 2 \\ \hline 1 & 1 & 2 \\ \hline \end{array}$$

	P_1	P_2	P_3
	0		0
		0	
	0		1
		0	1 2 2 0
	0		2
$\pi =$		0	2
	1		0
		1	0
	1		
		1	1
	1		1 2 2
		1	2

Greedy vs. Meta-heuristic



 Simulated Annealing, a type of local search algorithm, has been proven to be effective against CIT.³

³[SBSE'09] B. J. Garvin et al. "An improved meta-heuristic search for constrained interaction testing."

Greedy vs. Meta-heuristic



- Simulated Annealing, a type of local search algorithm, has been proven to be effective against CIT.³
- The followings are size and time comparisons between the greedy algorithm and the meta-heuristic algorithm (average of 50 runs).

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Greedy vs. Meta-heuristic



- Simulated Annealing, a type of local search algorithm, has been proven to be effective against CIT.³
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Size comparison

Subject Greedy Meta-heuristic SPIN-S 27 19 SPIN-V 42 36 GCC 24 21 Apache 42 32 21 Bugzilla 16

Time (sec.) comparison

Subject	Greedy	Meta-heuristic
SPIN-S	0.2	8.6
SPIN-V	11.3	102.1
GCC	204	1902.0
Apache	76.4	109.1
Bugzilla	1.9	9.1

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Summary



- 1. Equivalence Partitioning (EP)
- 2. Boundary Value Analysis (BVA)
- 3. Category Partition Method (CPM)
- 4. Combinatorial Testing (CT)

Covering Array (CA)

Fault Detection Effectiveness

Greedy Algorithm – IPOG Strategy

Greedy vs. Meta-heuristic

Next Lecture



Random Testing

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